

# **Final Product Change Notification**

# 202212003F01 : Discontinuation of Gross Leak Screening of Radio Power Metal Ceramic Packaged Devices

**Note:** This notice is NXP Company Proprietary.

Issue Date: Dec 14, 2022 Effective date: Mar 14, 2023

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#### **Management summary**

This PCN communicates the discontinuation of 100% Gross Leak testing from the final manufacturing flow of all Radio Power air cavity devices. This discontinuation is the result of tightened environmental regulations that have caused the gross leak fluid supplier to discontinue supply. No viable alternative suppliers or materials are available. Process yields and reliability testing demonstrate that this process is no longer necessary for long term reliable operation in the field.

### **Change Category**

	[ ]Wafer Fab Process	[X]Assembly Process	[]Product Marking	[]Test Process	[]Design
	[]Wafer Fab Materials	[]Assembly Materials	[]Mechanical Specification	[]Test Equipment	[]Errata
	[]Wafer Fab Location	[]Assembly Location	[]Packing/Shipping/Labeling	[]Test Location	[ ]Electrical spec./Test coverage
[]Firmware []Other					

PCN Overview Description

Gross Leak screening of all Radio Power air cavity metal ceramic packaged devices will be discontinued.

#### Reason

Tightened environmental regulations/restrictions on the chemical compounds required for gross leak testing have resulted in discontinuation of the supply of these chemicals. As a result, NXP will no longer be able to perform gross leak screening.

**Identification of Affected Products** 

Product identification does not change

## **Product Availability**

#### Sample Information Samples are available fromDec 04, 2022 Production Planned first shipmentMar 04, 2023 Anticipated Impact on Form, Fit, Function, Reliability or Quality

No Impact on form, fit, function, reliability or quality No Impact. Historically, screening yields have been very high and reliability testing of devices which do not pass the gross leak bubble test screening have passed all reliability tests without failure. **Data Sheet Revision** No impact to existing datasheet **Disposition of Old Products** Existing inventory will be shipped until depleted **Additional information** 

## Self qualification:<u>view online</u> **Timing and Logistics**

In compliance with JEDEC J-STD-046, your acknowledgement of this change is expected by Jan 13, 2023.

## **Contact and Support**

For all inquiries regarding the ePCN tool application or access issues, please contact NXP "Global Quality Support Team".

For all Quality Notification content inquiries, please contact your local NXP Sales Support team.

For specific questions on this notice or the products affected please contact our specialist directly:

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### NXP Quality Management Team.

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